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MRS Bulletin



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Organic single crystals

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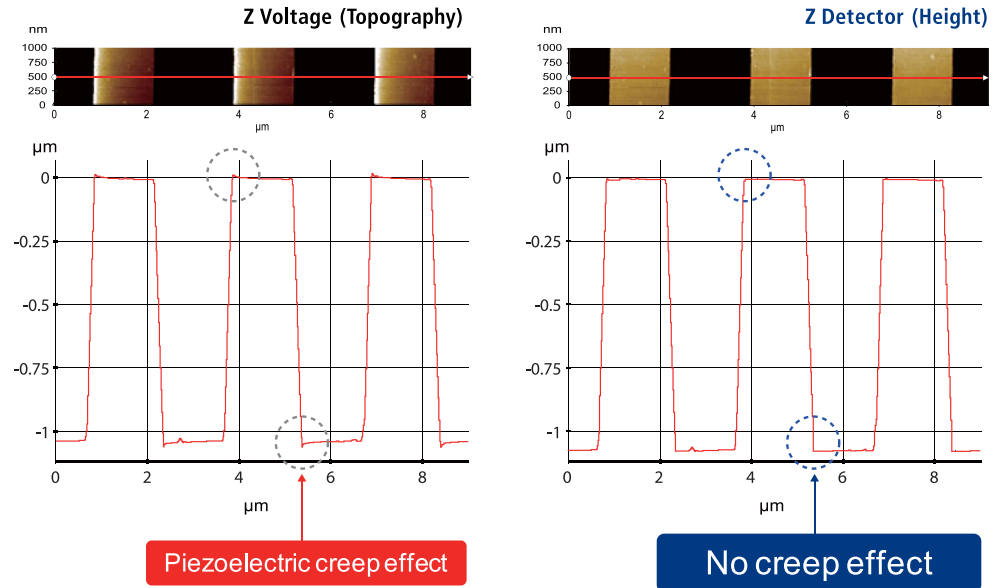
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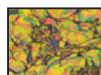
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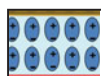
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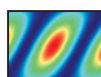
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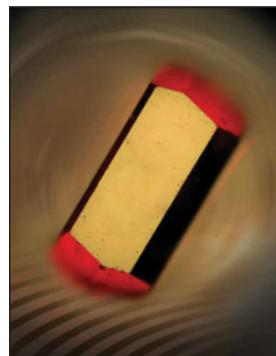
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ON THE COVER

Organic single crystals. This issue of *MRS Bulletin* provides an overview of the state of the art of the field of organic semiconductor single crystals, including materials, devices, and theories. The cover shows a single crystal of rubrene—the highest mobility organic semiconductor frequently used in experiments and modeling. Studies on rubrene reveal fundamental charge transport and optical properties of highly ordered molecular

materials relevant to organic electronics and photonics. The photograph is courtesy of Pavel Irkhin, Rutgers University. See the technical theme that begins on page 15.

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The Society's interdisciplinary approach differs from that of single-discipline professional societies because it promotes information exchange across the many technical fields touching materials development. MRS sponsors three major international annual meetings encompassing approximately 125 topical symposia, and also sponsors numerous single-topic scientific meetings. The Society recognizes professional and technical excellence and fosters technical interaction in local geographic regions through Sections and University Chapters.

MRS participates in the international arena of materials research through the International Union of Materials Research Societies (IUMRS). MRS is a member of the Alliance for Science & Technology Research in America and is an affiliate of the American Institute of Physics.

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